

Product Summary

$V_{(BR)DSS}$	$R_{DS(on)}$	I_D max $T_A = 25^\circ C$
30V	15m Ω @ $V_{GS} = 10V$	10.7A
	18.5m Ω @ $V_{GS} = 4.5V$	9.6A

Description and Applications

This new generation MOSFET has been designed to minimize the on-state resistance ($R_{DS(on)}$) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- DC-DC Converters
- Power management functions

Features

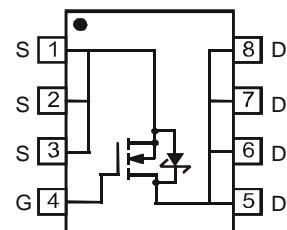
- DIOFET utilizes a unique patented process to monolithically integrate a MOSFET and a Schottky in a single die to deliver:
 - Low $R_{DS(ON)}$ - minimizes conduction losses
 - Low V_{SD} - reducing the losses due to body diode conduction
 - Low Q_{rr} - lower Q_{rr} of the integrated Schottky reduces body diode switching losses
 - Low gate capacitance (Q_g/Q_{gs}) ratio – reduces risk of shoot-through or cross conduction currents at high frequencies
 - Avalanche rugged – I_{AR} and E_{AR} rated
- Lead Free, RoHS Compliant (Note 1)
- "Green" Device (Note 2)
- ESD Protected
- Qualified to AEC-Q101 Standards for High Reliability

Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
- UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram Below
- Weight: 0.072 grams (approximate)



Top View


 Top View
 Internal Schematic

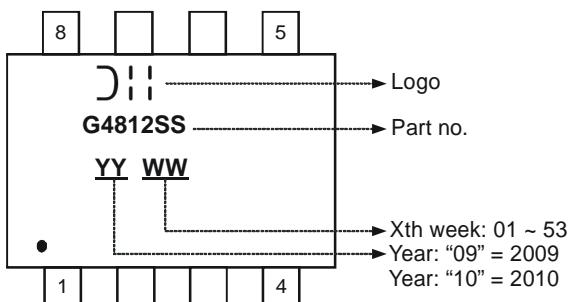
Ordering Information (Note 3)

Part Number	Case	Packaging
DMG4812SSS-13	SO-8	2500 / Tape & Reel

Notes:

1. No purposefully added lead.
2. Diodes Inc.'s "Green" policy can be found on our website at <http://www.diodes.com>.
3. For packaging details, go to our website at <http://www.diodes.com>.

Marking Information



Maximum Ratings @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	30	V
Gate-Source Voltage			V_{GSS}	± 12	V
Continuous Drain Current (Note 4) $V_{GS} = 10\text{V}$	Steady State	$T_A = 25^\circ\text{C}$ $T_A = 85^\circ\text{C}$	I_D	8 6.4	A
Continuous Drain Current (Note 5) $V_{GS} = 10\text{V}$	$t \leq 10 \text{ sec}$	$T_A = 25^\circ\text{C}$ $T_A = 85^\circ\text{C}$	I_D	10.7 8.6	A
Continuous Drain Current (Note 5) $V_{GS} = 4.5\text{V}$	$t \leq 10 \text{ sec}$	$T_A = 25^\circ\text{C}$ $T_A = 85^\circ\text{C}$	I_D	9.6 7.7	A
Pulsed Drain Current (Note 6)			I_{DM}	45	A
Avalanche Current (Notes 6 & 7)			I_{AR}	13	A
Repetitive Avalanche Energy (Notes 6 & 7) $L = 0.3\text{mH}$			E_{AR}	25.4	mJ

Thermal Characteristics

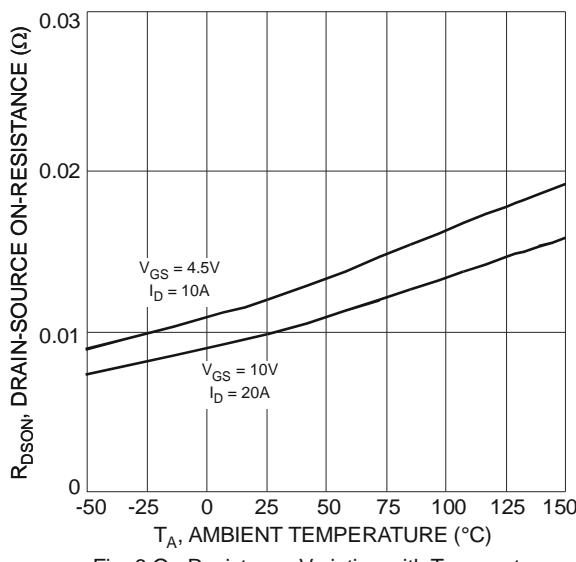
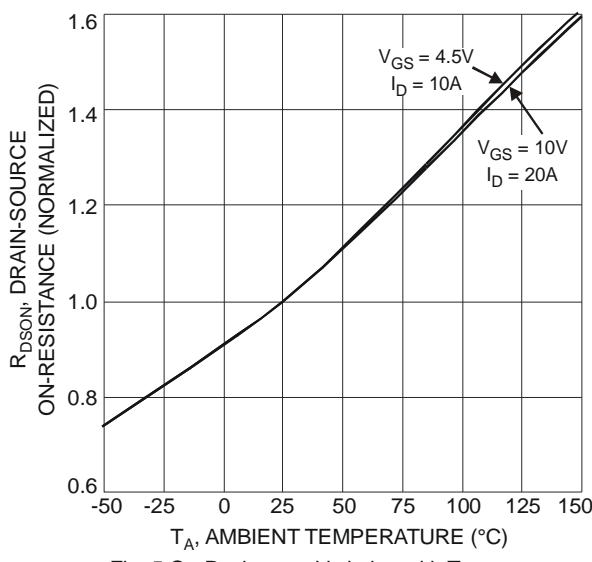
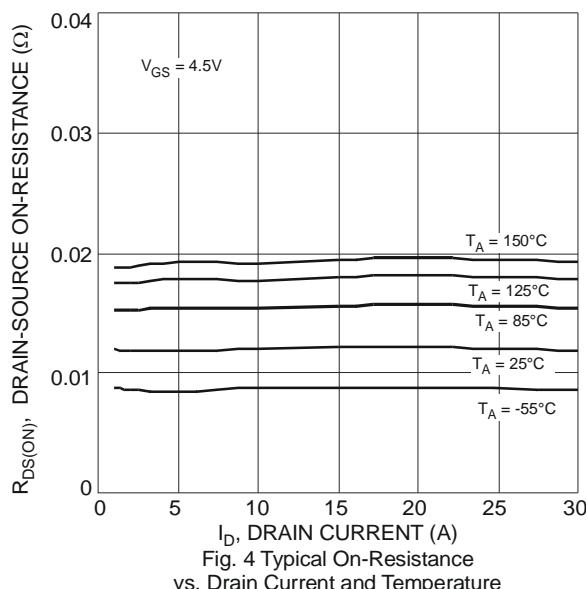
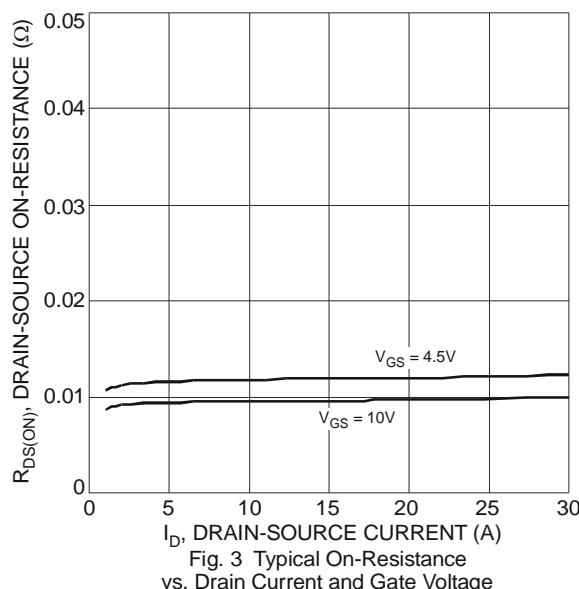
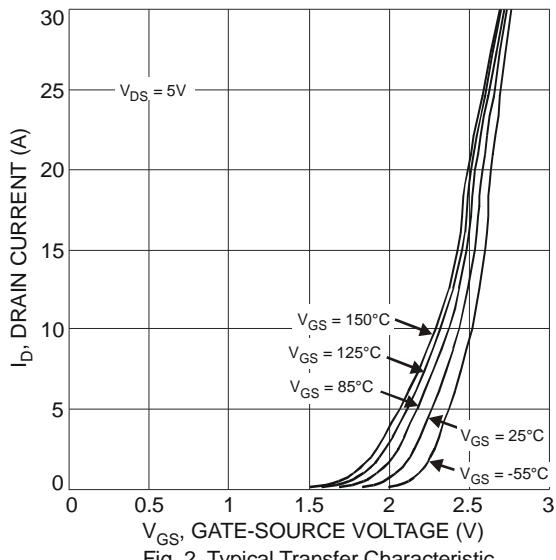
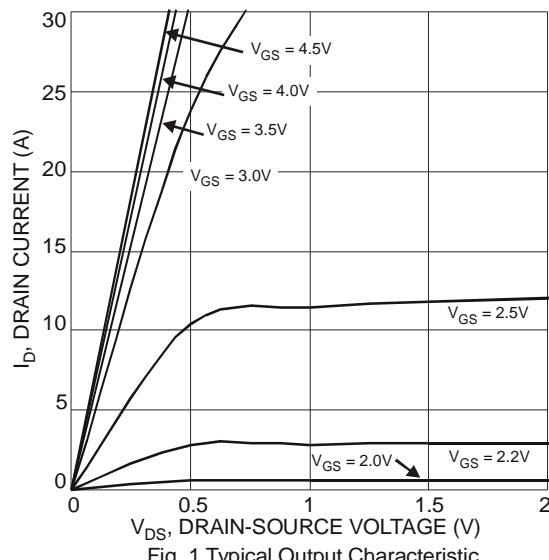
Characteristic			Symbol	Value	Unit
Power Dissipation (Note 4)			P_D	1.54	W
Thermal Resistance, Junction to Ambient @ $T_A = 25^\circ\text{C}$ (Note 4)			$R_{\theta JA}$	81	$^\circ\text{C}/\text{W}$
Power Dissipation (Note 5)			P_D	2.8	W
Thermal Resistance, Junction to Ambient @ $T_A = 25^\circ\text{C}$ (Note 5)			$R_{\theta JA}$	45	$^\circ\text{C}/\text{W}$
Operating and Storage Temperature Range			T_J, T_{STG}	-55 to +150	$^\circ\text{C}$

Electrical Characteristics @ $T_A = 25^\circ\text{C}$ unless otherwise stated

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV_{DSS}	30	-	-	V	$V_{GS} = 0\text{V}, I_D = 1\text{mA}$
Zero Gate Voltage Drain Current	I_{DSS}	-	-	150	μA	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	-	-	± 100	nA	$V_{GS} = \pm 12\text{V}, V_{DS} = 0\text{V}$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	$V_{GS(\text{th})}$	1.0	-	2.3	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS}(\text{ON})$	-	11	15	$\text{m}\Omega$	$V_{GS} = 10\text{V}, I_D = 10.7\text{A}$
		-	16.5	18.5		$V_{GS} = 4.5\text{V}, I_D = 9.6\text{A}$
Forward Transfer Admittance	$ Y_{fs} $	-	20	-	S	$V_{DS} = 5\text{V}, I_D = 10.7\text{A}$
Diode Forward Voltage	V_{SD}	-	0.36	0.5	V	$V_{GS} = 0\text{V}, I_S = 1\text{A}$
Maximum Body-Diode + Schottky Continuous Current	I_S	-	-	5	A	-
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C_{iss}	-	1849	-	pF	$V_{DS} = 15\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	-	158	-	pF	
Reverse Transfer Capacitance	C_{rss}	-	123	-	pF	
Gate Resistance	R_g	0.54	2.0	4.0	Ω	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$
Total Gate Charge $V_{GS} = 4.5\text{V}$	Q_g	-	18.5	-	nC	$V_{DS} = 15\text{V}, V_{GS} = 10\text{V}, I_D = 9.6\text{A}$
Total Gate Charge $V_{GS} = 10\text{V}$	Q_g	-	43	-	nC	
Gate-Source Charge	Q_{gs}	-	4.7	-	nC	
Gate-Drain Charge	Q_{gd}	-	4.0	-	nC	
Turn-On Delay Time	$t_{D(\text{on})}$	-	6.62	-	ns	$V_{GS} = 10\text{V}, V_{DS} = 15\text{V}, R_G = 3\Omega, R_L = 15\Omega, I_D = 1\text{A}$
Turn-On Rise Time	t_r	-	8.73	-	ns	
Turn-Off Delay Time	$t_{D(\text{off})}$	-	36.41	-	ns	
Turn-Off Fall Time	t_f	-	4.69	-	ns	

Notes:

- Device mounted on FR-4 PCB with minimum recommended pad layout. The value in any given application depends on the user's specific board design.
- Device mounted on 1" x 1" FR-4 PCB with high coverage 1 oz. Copper, single sided, device is measured at $t \leq 10 \text{ sec}$.
- Repetitive rating, pulse width limited by junction temperature.
- I_{AR} and E_{AR} rating are based on low frequency and duty cycles to keep $T_J = 25^\circ\text{C}$
- Short duration pulse test used to minimize self-heating effect.
- Guaranteed by design. Not subject to production testing.



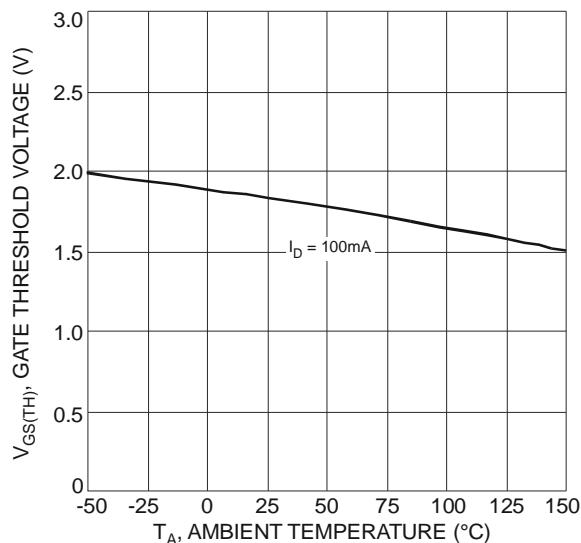


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

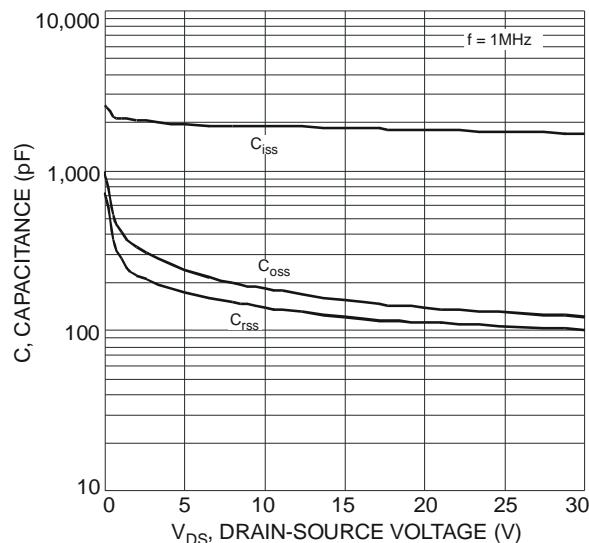


Fig. 9 Typical Total Capacitance

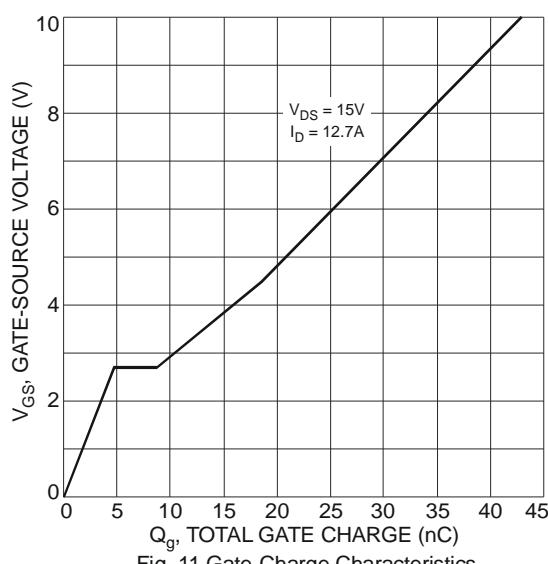


Fig. 11 Gate-Charge Characteristics

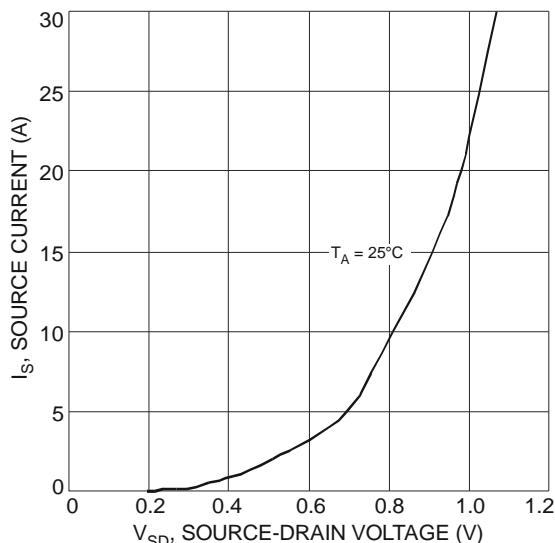


Fig. 8 Diode Forward Voltage vs. Current

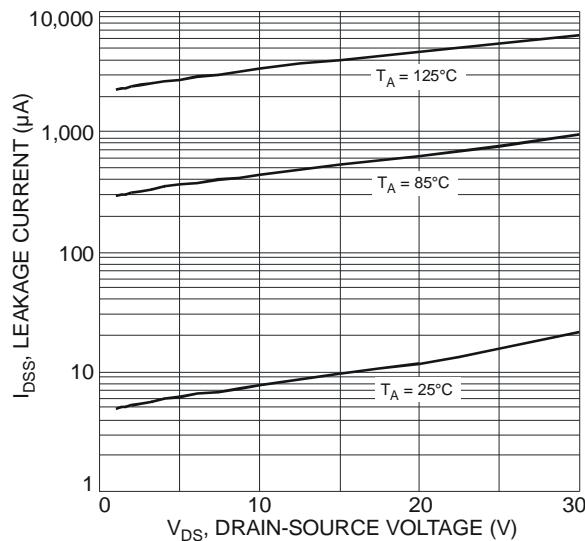
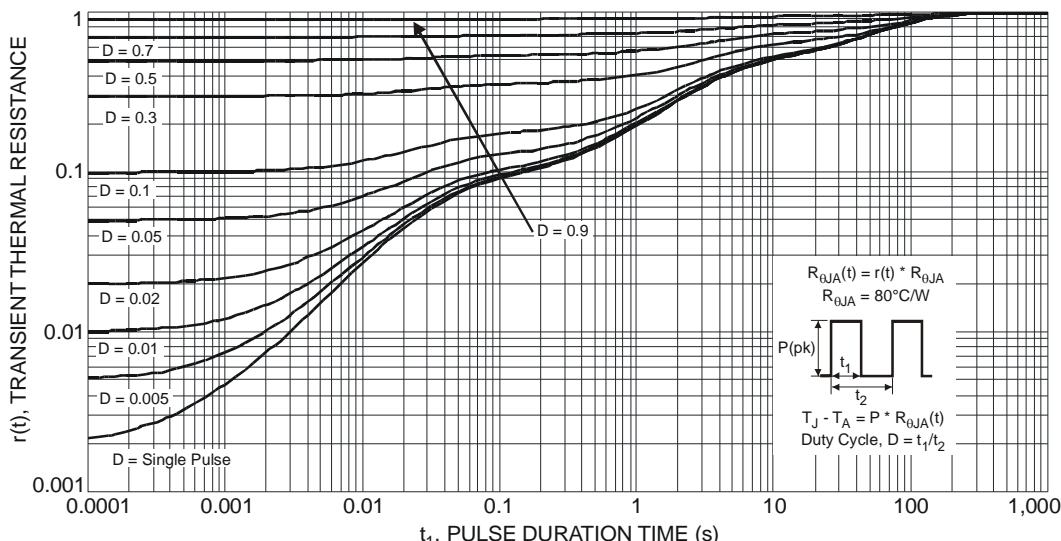
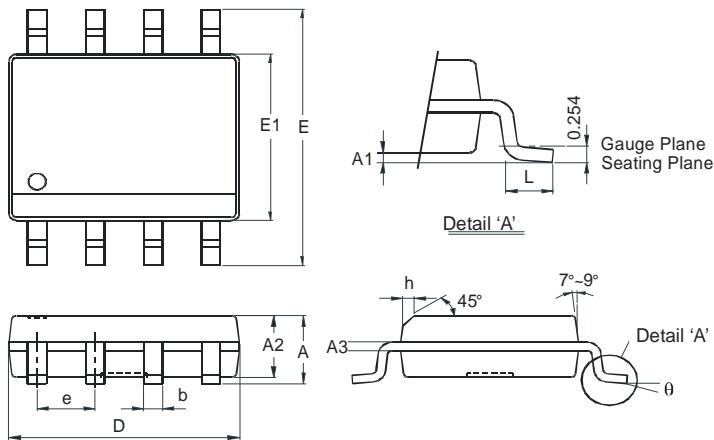


Fig. 10 Typical Leakage Current
vs. Drain-Source Voltage



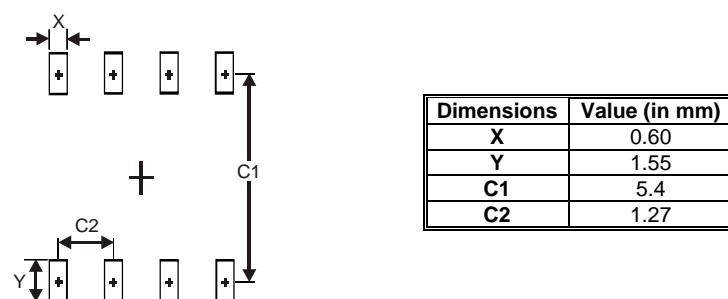
Package Outline Dimensions



SO-8		
Dim	Min	Max
A	-	1.75
A1	0.10	0.20
A2	1.30	1.50
A3	0.15	0.25
b	0.3	0.5
D	4.85	4.95
E	5.90	6.10
E1	3.85	3.95
e	1.27 Typ	
h	-	0.35
L	0.62	0.82
θ	0°	8°

All Dimensions in mm

Suggested Pad Layout



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